



# 10-Bit, 40MSPS, TTL-Output ADC

MAX1161

## General Description

The MAX1161 10-bit, monolithic analog-to-digital converter (ADC) is capable of 40MSPS minimum word rates. An on-board track/hold ensures excellent dynamic performance without the need for external components. A 5pF input capacitance minimizes drive requirement problems.

Inputs and outputs are TTL compatible. An overrange output is provided to indicate overflow conditions. Output data format is straight binary. Power dissipation is low at only 1W with +5V and -5.2V power-supply voltages. The MAX1161 also accepts wide,  $\pm 2V$  input voltages.

The MAX1161 is available in 28-pin DIP and SO packages in the commercial temperature range.

## Applications

Medical Imaging  
Professional Video  
Radar Receivers  
Instrumentation  
Digital Communications

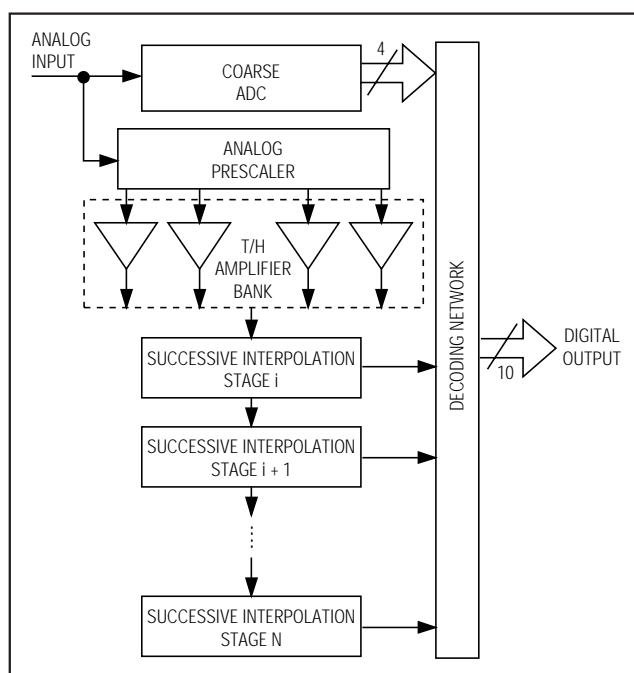
## Features

- ♦ Monolithic 40MSPS Converter
- ♦ On-Chip Track/Hold
- ♦ Bipolar,  $\pm 2V$  Analog Input
- ♦ 57dB SNR at 3.58MHz Input
- ♦ 5pF Input Capacitance
- ♦ TTL Outputs

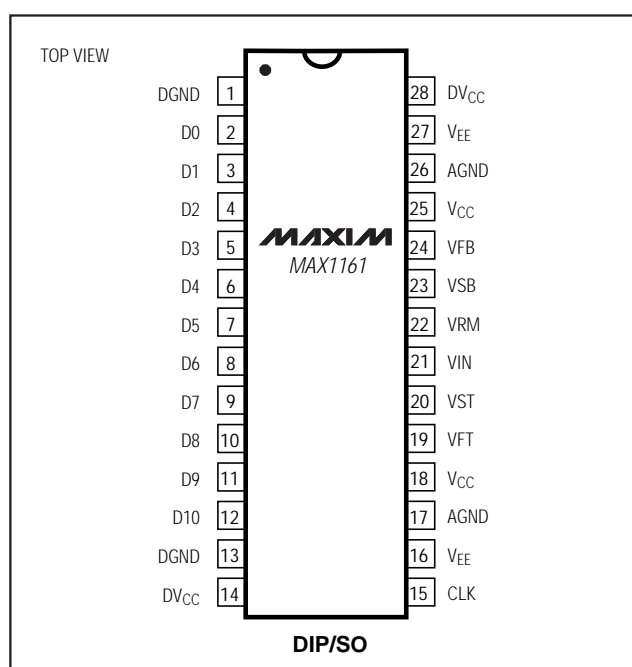
## Ordering Information

PART	TEMP. RANGE	PIN-PACKAGE
MAX1161ACPI	0°C to +70°C	28 Wide Plastic DIP
MAX1161BCPI	0°C to +70°C	28 Wide Plastic DIP
MAX1161ACWI	0°C to +70°C	28 SO
MAX1161BCWI	0°C to +70°C	28 SO

## Functional Diagram



## Pin Configuration



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## ABSOLUTE MAXIMUM RATINGS

V <sub>CC</sub> .....	+6V	Continuous Power Dissipation (T <sub>A</sub> = +70°C)	
V <sub>EE</sub> .....	-6V	Plastic DIP .....	1.14W
Analog Input.....	V <sub>FB</sub> ≤ V <sub>IN</sub> ≤ V <sub>FT</sub>	SO .....	1W
V <sub>FT</sub> , V <sub>FB</sub> .....	3V, -3V	Operating Temperature Range.....	0°C to +70°C
Reference-Ladder Current.....	12mA	Junction Temperature .....	+150°C
CLK Input.....	V <sub>CC</sub>	Storage Temperature Range .....	-65°C to +150°C
Digital Outputs.....	30mA to -30mA	Lead Temperature (soldering, 10sec) .....	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS

(V<sub>CC</sub> = +5.0V, V<sub>EE</sub> = -5.2V, DV<sub>CC</sub> = +5.0V, V<sub>IN</sub> = ±2.0V, V<sub>SB</sub> = -2.0V, V<sub>ST</sub> = +2.0V, f<sub>CLK</sub> = 40MHz, 50% clock duty cycle, T<sub>A</sub> = T<sub>MIN</sub> to T<sub>MAX</sub>, unless otherwise noted.)

PARAMETER	CONDITIONS	TEST LEVEL	MAX1161A			MAX1161B			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
Resolution			10			10			Bits
<b>DC ACCURACY</b> (±full scale, 250kHz sample rate, T <sub>A</sub> = +25°C)									
Integral Nonlinearity		I		±1.0			±1.5		LSB
Differential Nonlinearity		I		±0.5			±0.75		LSB
No Missing Codes				Guaranteed			Guaranteed		
<b>ANALOG INPUT</b>									
Input Voltage Range		VI		±2.0			±2.0		V
Input Bias Current	V <sub>IN</sub> = 0V	VI		30	60		30	60	μA
Input Bias Current	T <sub>A</sub> = -55°C to +125°C	VI			75			75	μA
Input Resistance		VI	100	300		100	300		kΩ
Input Resistance	T <sub>A</sub> = -55°C to +125°C	VI	75	300		75	300		kΩ
Input Capacitance		VI		5			5		pF
Input Bandwidth	3dB small signal	V		120			120		MHz
Positive Full-Scale Error		V		±2.0			±2.0		LSB
Negative Full-Scale Error		V		±2.0			±2.0		LSB
<b>REFERENCE INPUT</b>									
Reference-Ladder Resistance		VI	500	800		500	800		Ω
Reference-Ladder Tempco		V			0.8			0.8	Ω/°C
<b>TIMING CHARACTERISTICS</b>									
Maximum Conversion Rate		VI	40			40			MHz
Overvoltage Recovery Time		V		20			20		ns
Pipeline Delay (Latency)		VI			1			1	Clock Cycle
Output Delay	T <sub>A</sub> = +25°C	V		14	18		14	18	ns
Aperture Delay Time	T <sub>A</sub> = +25°C	V		1			1		ns
Aperture Jitter Time	T <sub>A</sub> = +25°C	V		5			5		ps-RMS
Acquisition Time	T <sub>A</sub> = +25°C	V		12			12		ns

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## ELECTRICAL CHARACTERISTICS (continued)

(V<sub>CC</sub> = +5.0V, V<sub>EE</sub> = -5.2V, DV<sub>CC</sub> = +5.0V, V<sub>IN</sub> = ±2.0V, V<sub>SB</sub> = -2.0V, V<sub>ST</sub> = +2.0V, f<sub>CLK</sub> = 40MHz, 50% clock duty cycle, T<sub>A</sub> = T<sub>MIN</sub> to T<sub>MAX</sub>, unless otherwise noted.)

PARAMETER	CONDITIONS		TEST LEVEL	MAX1161A MIN TYP MAX			MAX1161B MIN TYP MAX			UNITS
DYNAMIC PERFORMANCE										
Effective Number of Bits (ENOB)	f <sub>IN</sub> = 1MHz			8.7			8.2			Bits
	f <sub>IN</sub> = 3.58MHz			8.7			8.2			
	f <sub>IN</sub> = 10.0MHz			7.3			6.9			
Signal-to-Noise Ratio (without harmonics) (SNR)	f <sub>IN</sub> = 1MHz	T <sub>A</sub> = +25°C	I	55	57		52	54		dB
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	53	55		50	52		
	f <sub>IN</sub> = 3.58MHz	T <sub>A</sub> = +25°C	I	55	57		52	54		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	53	55		50	52		
	f <sub>IN</sub> = 10.0MHz	T <sub>A</sub> = +25°C	I	48	50		46	48		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	45	47		43	45		
Total Harmonic Distortion (THD)	f <sub>IN</sub> = 1MHz	T <sub>A</sub> = +25°C	I	54	56		52	54		dB
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	51	53		49	51		
	f <sub>IN</sub> = 3.58MHz	T <sub>A</sub> = +25°C	I	54	56		52	54		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	51	53		49	51		
	f <sub>IN</sub> = 10.0MHz	T <sub>A</sub> = +25°C	I	46	48		43	45		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	45	47		41	44		
Signal-to-Noise and Distortion Ratio (SINAD)	f <sub>IN</sub> = 1MHz	T <sub>A</sub> = +25°C	I	52	54		49	51		dB
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	49			46			
	f <sub>IN</sub> = 3.58MHz	T <sub>A</sub> = +25°C	I	52	54		49	51		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	49			46			
	f <sub>IN</sub> = 10.0MHz	T <sub>A</sub> = +25°C	I	44	46		41	43		
		T <sub>A</sub> = 0°C to +70°C, T <sub>A</sub> = -25°C to +85°C	IV	43			40			
Spurious-Free Dynamic Range (SFDR)	f <sub>IN</sub> = 1MHz	T <sub>A</sub> = +25°C	V	67			67			dB
Differential Phase	f <sub>IN</sub> = 3.58MHz, 4.35MHz	T <sub>A</sub> = +25°C	V	0.2			0.2			Degrees
Differential Gain	f <sub>IN</sub> = 3.58MHz, 4.35MHz	T <sub>A</sub> = +25°C	V	0.5			0.7			%

# 10-Bit, 40Mps, TTL-Output ADC

## ELECTRICAL CHARACTERISTICS (continued)

( $V_{CC} = +5.0V$ ,  $V_{EE} = -5.2V$ ,  $DV_{CC} = +5.0V$ ,  $V_{IN} = \pm 2.0V$ ,  $V_{SB} = -2.0V$ ,  $V_{ST} = +2.0V$ ,  $f_{CLK} = 40MHz$ , 50% clock duty cycle,  $T_A = T_{MIN}$  to  $T_{MAX}$ , unless otherwise noted.)

PARAMETER	CONDITIONS	TEST LEVEL	MAX1161A MIN TYP MAX			MAX1161B MIN TYP MAX			UNITS
DIGITAL INPUTS									
Logic 1 Voltage		V	2.4		4.5	2.4		4.0	V
Logic 0 Voltage		V			0.8			0.8	V
Maximum Input Current Low	T <sub>A</sub> = +25°C	IV	0	5	20	0	5	20	μA
Maximum Input Current High	T <sub>A</sub> = +25°C	IV	0	5	20	0	5	20	μA
Pulse Width Low (CLK)		IV	10			10			ns
Pulse Width High (CLK)		IV	10		300	10		300	ns
DIGITAL OUTPUTS									
Logic 1 Voltage		IV	2.4			2.4			V
Logic 0 Voltage		IV			0.6			0.6	V
POWER-SUPPLY REQUIREMENTS									
Voltages	V <sub>CC</sub>	IV	4.75		5.25	4.75		5.25	V
	DV <sub>CC</sub>	IV	4.75	5.0	5.25	4.75	5.0	5.25	
	-V <sub>EE</sub>	IV	-4.95	-5.2	-5.45	-4.95	-5.2	-5.45	
Currents	I <sub>CC</sub>	VI		118	145		118	145	mA
	DI <sub>CC</sub>	VI		40	55		40	55	
	-I <sub>EE</sub>	VI		40	57		40	57	
Power Dissipation		VI		1.0	1.3		1.0	1.3	W
Power-Supply Rejection	V <sub>CC</sub> = 5V ±0.25V, V <sub>EE</sub> = -5.2V ±0.25V	V		1.0			1.0		LSB

### TEST LEVEL CODES

All electrical characteristics are subject to the following conditions: All parameters having min/max specifications are guaranteed. The Test Level column indicates the specific device testing actually performed during production and Quality Assurance inspection. Any blank section in the data column indicates that the specification is not tested at the specified condition.

Unless otherwise noted, all tests are pulsed; therefore,  $T_j = T_C = T_A$ .

### TEST LEVEL TEST PROCEDURE

- |     |   |
|-----|---|
| I   | 100% production tested at the specified temperature.  |
| II  | 100% production tested at $T_A = +25^\circ C$ , and sample tested at the specified temperatures.          |
| III | QA sample tested only at the specified temperatures.  |
| IV  | Parameter is guaranteed (but not tested) by design and characterization data.                             |
| V   | Parameter is a typical value for information purposes only.   |
| VI  | 100% production tested at $T_A = +25^\circ C$ . Parameter is guaranteed over specified temperature range. |

## Pin Description

PIN	NAME	FUNCTION
1, 13	DGND	Digital Ground
2	D0	TTL Output (LSB)
3–10	D1–D8	TTL Outputs
11	D9	TTL Output (MSB)
12	D10	TTL Output Overrange
14, 28	$DV_{CC}$	+5V Supply (digital)
15	CLK	Clock
16, 27	$V_{EE}$	-5.2V Supply (analog)

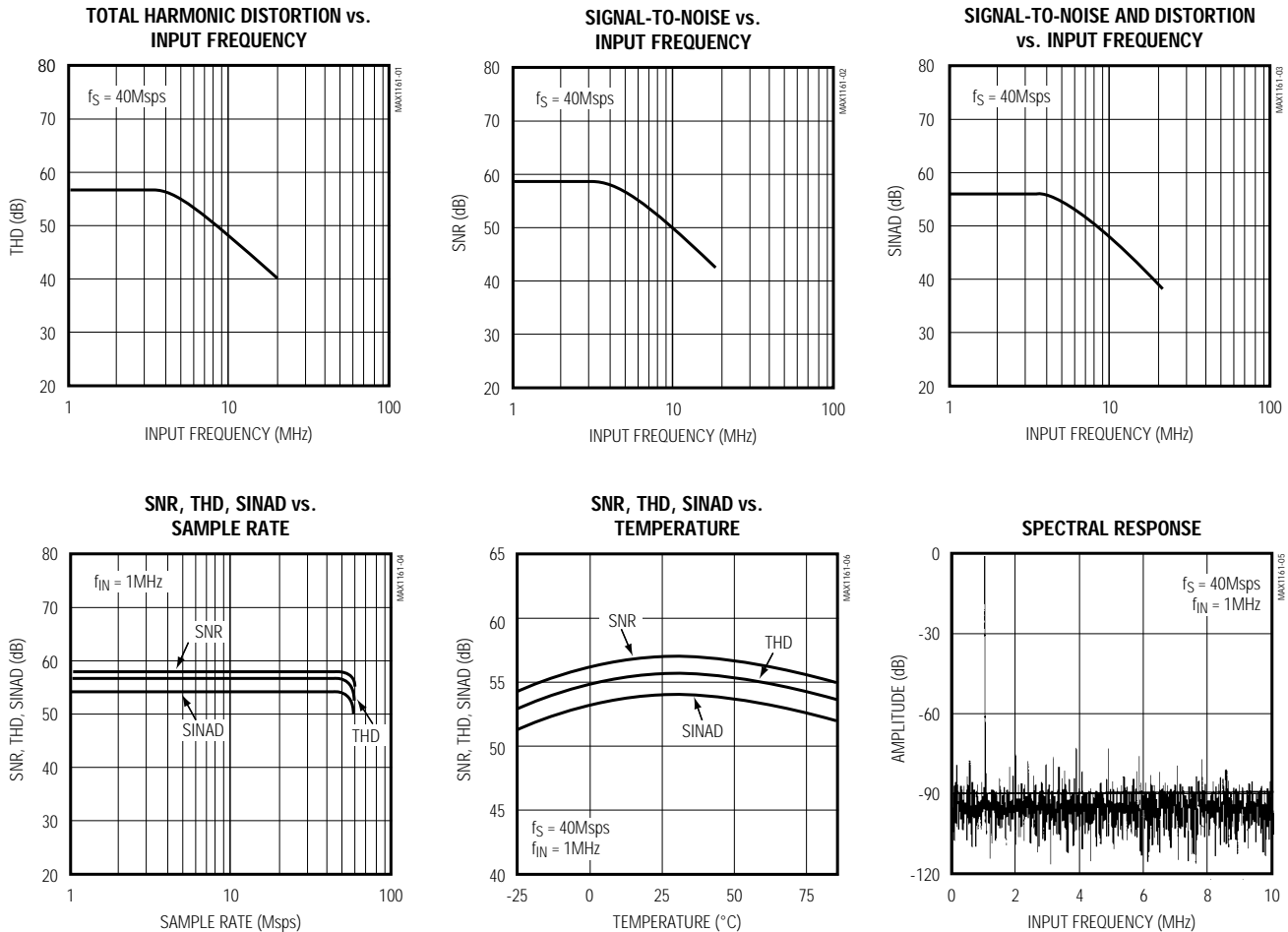
PIN	NAME	FUNCTION
17, 26	AGND	Analog Ground
18, 25	$V_{CC}$	+5V Supply (analog)
19	VFT	Force for Top of Reference Ladder
20	VST	Sense for Top of Reference Ladder
21	$V_{IN}$	Analog Input
22	VRM	Middle of Voltage Reference Ladder
23	$V_{SB}$	Sense for Bottom of Reference Ladder
24	VFB	Force for Bottom of Reference Ladder

# 10-Bit, 40Mps, TTL-Output ADC

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## Typical Operating Characteristics

( $T_A = +25^\circ\text{C}$ , unless otherwise noted.)



## Detailed Description

The MAX1161 requires few external components to achieve the stated operation and performance. Figure 2 shows the typical interface requirements when using the MAX1161 in normal circuit operation. The following section provides a description of the pin functions, and outlines critical performance criteria to consider for achieving optimal device performance.

### Power Supplies and Grounding

The MAX1161 requires -5.2V and +5V analog supply voltages. The +5V supply is common to analog  $V_{CC}$  and digital  $DV_{CC}$ . A ferrite bead in series with each supply line reduces the transient noise injected into the analog

$V_{CC}$ . These beads should be connected as close to the device as possible. The connection between the beads and the MAX1161 should not be shared with any other device. Bypass each power-supply pin as close to the device as possible. Use  $0.1\mu\text{F}$  for  $V_{EE}$  and  $V_{CC}$ , and  $0.01\mu\text{F}$  for  $DV_{CC}$  (chip capacitors are recommended).

The MAX1161 has two grounds: AGND and DGND. These internal grounds are isolated on the device. Use ground planes for optimum device performance. Use DGND for the  $DV_{CC}$  return path (typically 40mA) and for the return path for all digital output logic interfaces. Separate AGND and DGND from each other, connecting them together only through a ferrite bead at the device.

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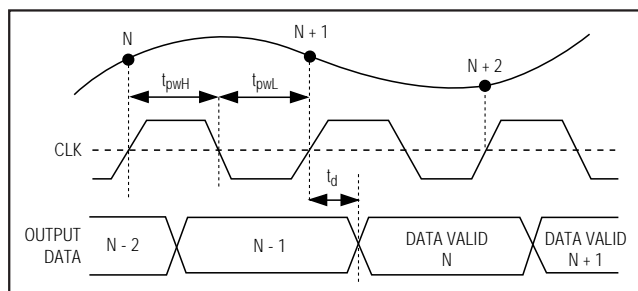


Figure 1a. Timing Diagram

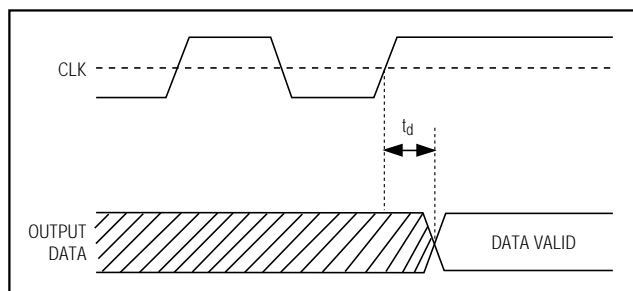


Figure 1b. Single-Event Clock

**Table 1. Timing Parameters**

PARAMETER	DESCRIPTION	MIN	TYP	MAX	UNITS
$t_d$	CLK to Data Valid Propagation Delay		14	18	ns
$t_{pwH}$	CLK High Pulse Width	10		300	ns
$t_{pwL}$	CLK Low Pulse Width	10			ns

Connect a Schottky or hot carrier diode between AGND and  $V_{EE}$ . The use of separate power supplies between  $V_{CC}$  and  $DV_{CC}$  is not recommended due to potential power-supply-sequencing latchup conditions. For optimum performance, use the recommended circuit shown in Figure 2.

## Voltage Reference

The MAX1161 requires the use of two voltage references: VFT and VFB. VFT is the force for the top of the voltage-reference ladder (typically +2.5V); VFB (typically -2.5V) is the force for the bottom of the voltage-reference ladder. Both voltages are applied across an 800 $\Omega$  internal reference-ladder resistance. The +2.5V voltage source for reference VFT must be current limited to 20mA (max) if a different driving circuit is used in place of the recommended reference circuit shown in Figures 2 and 3. In addition, there are three reference-ladder taps (VST, VRM, and VSB). VST is the sense for the top of the reference ladder (+2V), VRM is the mid-point of the ladder (typically 0V), and VSB is the sense for the bottom of the reference ladder (-2V). The voltages at VST and VSB are the device's true full-scale input voltages when VFT and VFB are driven to the recommended voltages (+2.5V and -2.5V, respectively). These points should be used to monitor the device's actual full-scale input range. When not being used, a decoupling capacitor of 0.01 $\mu$ F (chip carrier preferred) connected to AGND from each tap is recommended to minimize high-frequency noise injection.

Figure 2 shows an example of a recommended reference-driver circuit. IC1 (MAX6225) is a +2.5V reference with 0.2% accuracy. Potentiometer R1 is 10k $\Omega$  and supports a minimum adjustable range of 0.6%. Use an OP07 or equivalent device for IC2. R2 and R3 must be matched to within 0.1% with good TC tracking to maintain 0.3LSB matching between VFT and VFB. If 0.1% matching is not met, then R4 can be used to adjust the VFB voltage to the desired level. Adjust VFT and VFB such that VST and VSB are exactly +2V and -2V, respectively.

The analog input range scales proportionally with respect to the reference voltage if a different input range is required. The maximum scaling factor for device operation is  $\pm 20\%$  of the recommended reference voltages of VFT and VFB. However, because the device is laser trimmed to optimize performance with  $\pm 2.5$ V references, its accuracy degrades if operated beyond a  $\pm 2\%$  range.

The following errors are defined:

$$\begin{aligned} +FS \text{ error} &= \text{top of ladder offset voltage} \\ &= \Delta (+FS - VST + 1\text{LSB}) \end{aligned}$$

$$\begin{aligned} -FS \text{ error} &= \text{bottom of ladder offset voltage} \\ &= \Delta (-FS - VSB - 1\text{LSB}) \end{aligned}$$

where the +FS (full-scale) input voltage is defined as the output transition between 11 1111 1110 and 11 1111 1111, and the -FS input voltage is defined as the output transition between 00 0000 0000 and 00 0000 0001 (Table 2).

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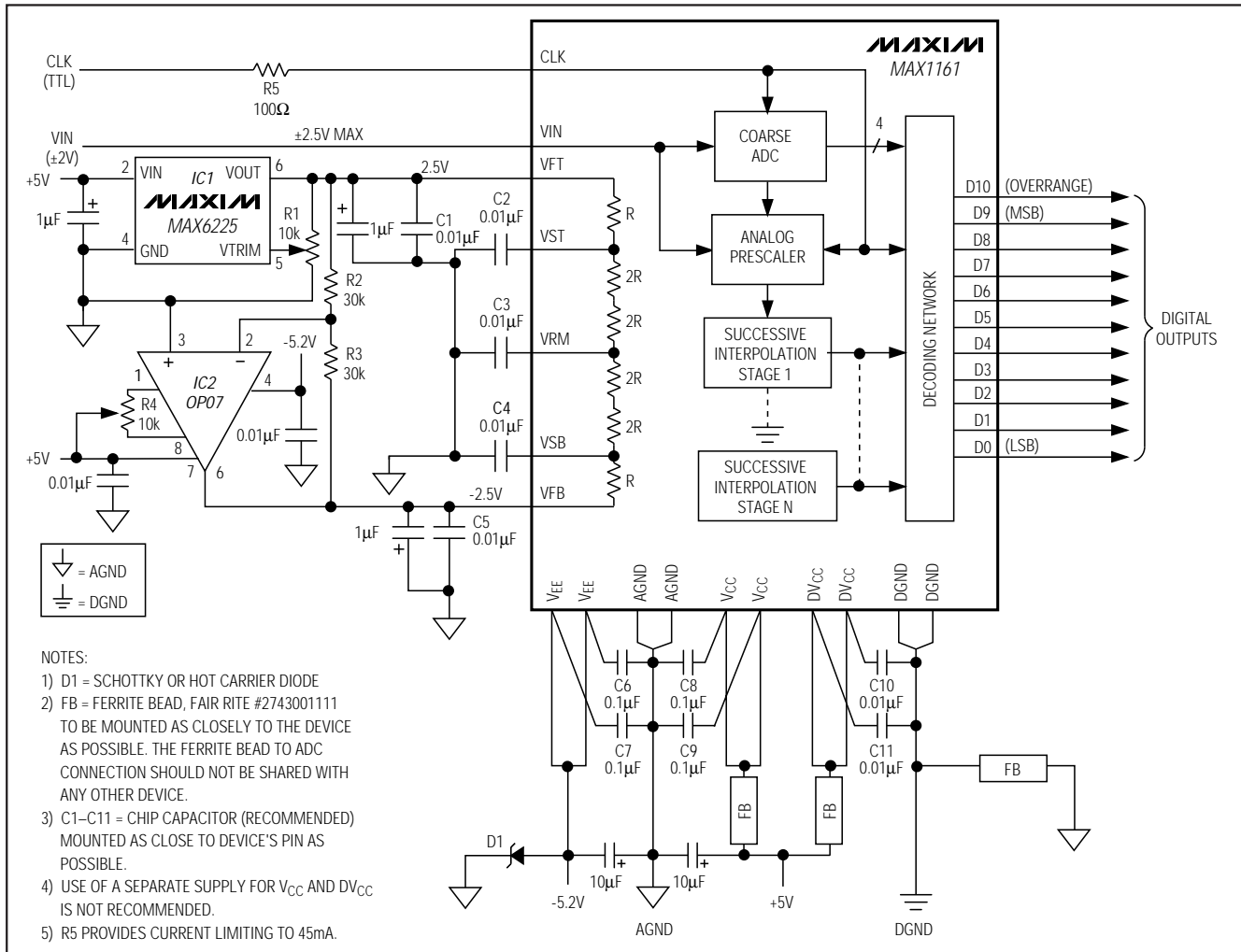


Figure 2. Typical Operating Circuit

## Analog Input

VIN is the analog input. The full-scale input range will be 80% of the reference voltage, or  $\pm 2V$  with  $V_{FB} = -2.5V$  and  $V_{FT} = +2.5V$ .

The analog input's drive requirements are minimal when compared to conventional flash converters. This is due to the MAX1161's extremely low (5pF) input capacitance and very high (300k $\Omega$ ) input resistance. For example, for an input signal of  $\pm 2V_{p-p}$  with a 10MHz input frequency, the peak output current required for the driving circuit is only 628 $\mu A$ .

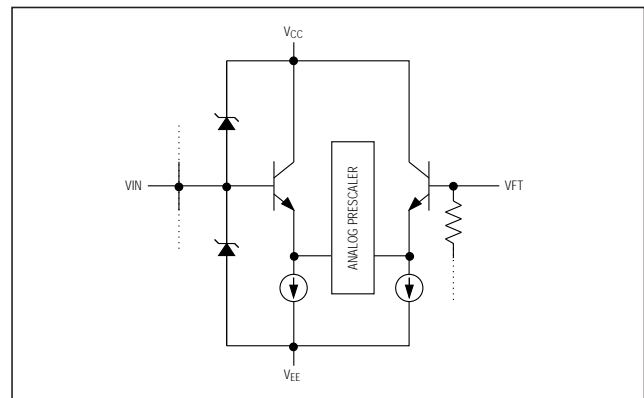


Figure 3. Analog Equivalent Input Circuit

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**Table 2. Output Data Information**

ANALOG INPUT	OVERRANGE D10	OUTPUT CODE D9–D0
$> +2V + 1/2\text{LSB}$	1	11 1111 1111
$+2V - 1\text{LSB}$	0	11 1111 1110
0.0V	0	00 0000 0000
$-2V + 1\text{LSB}$	0	00 0000 0000
$< -2V$	0	00 0000 0000

(0 indicates the flickering bit between logic 0 and 1.)

## Clock Input

The MAX1161 is driven from a single-ended TTL input (CLK). The CLK pulse width ( $t_{pWH}$ ) must be kept between 10ns and 300ns to ensure proper operation of the internal track/hold amplifier (Figure 1a). When operating the MAX1161 at sampling rates above 3MSPS, it is recommended that the clock input duty cycle be kept at 50% to optimize performance (Figure 4). The analog input signal is latched on the rising edge of CLK.

The clock input must be driven from fast TTL logic ( $V_{IH} \leq 4.5V$ ,  $t_{RISE} < 6\text{ns}$ ). In the event the clock is driven from a high current source, use a  $100\Omega$  resistor (R5) in series to limit current to approximately 45mA.

## Digital Outputs

The format of the output data (D0–D9) is straight binary (Table 2). The outputs are latched on the rising edge of CLK with a propagation delay typically at 14ns. There is a one-clock-cycle latency between CLK and the valid output data (Figure 1a).

The digital outputs' rise and fall times are not symmetrical. Typical propagation delay is 14ns for the rise time and 6ns for the fall time (Figure 5). The nonsymmetrical rise and fall times create approximately 8ns of invalid data.

## Overrange Output

The overrange output (D10) is an indication that the analog input signal has exceeded the positive full-scale input voltage by 1LSB. When this condition occurs, D10 will switch to logic 1. All other data outputs (D0–D9) will remain at logic 1 as long as D10 remains at logic 1. This feature makes it possible to include the MAX1161 in higher-resolution systems.

## Evaluation Board

The MAX1160 EV kit is available to help designers demonstrate the MAX1160 or MAX1161's full performance. This board includes a reference circuit, clock-driver circuit, output data latches, and an on-board reconstruction of the digital data. A separate data sheet describing the operation of this board is also available. Contact the factory for price and availability.

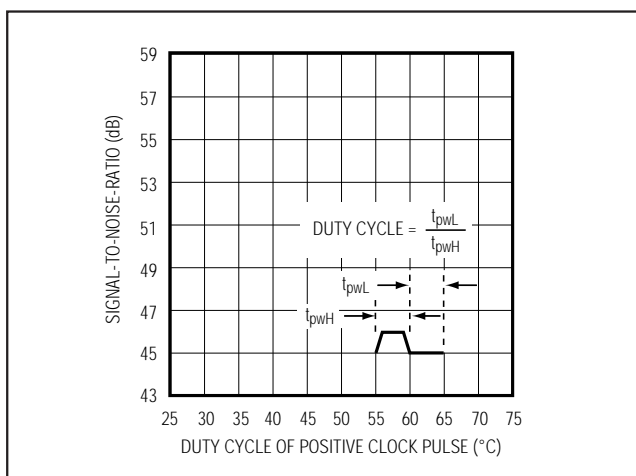


Figure 4. SNR vs. Clock Duty Cycle

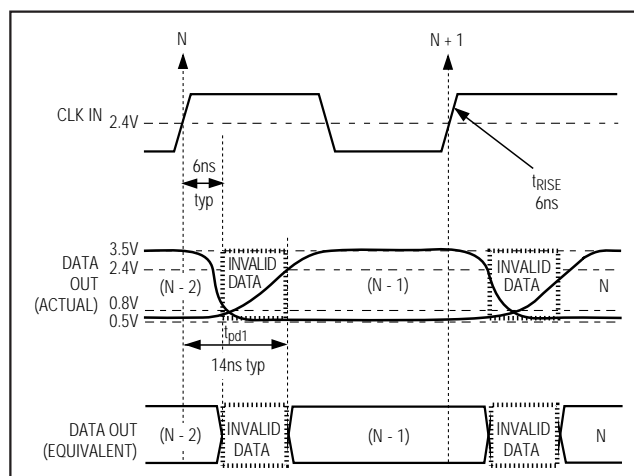


Figure 5. Digital Output Characteristics

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